

# SMPS MOSFET IRFPS38N60L

HEXFET® Power MOSFET

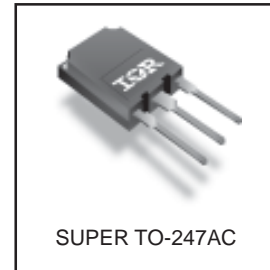
## Applications

- Zero Voltage Switching SMPS
- Telecom and Server Power Supplies
- Uninterruptible Power Supplies
- Motor Control applications

V <sub>DSS</sub>	R <sub>DS(on) typ.</sub>	T <sub>rr typ.</sub>	I <sub>D</sub>
600V	120mΩ	170ns	38A

## Features and Benefits

- SuperFast body diode eliminates the need for external diodes in ZVS applications.
- Lower Gate charge results in simpler drive requirements.
- Enhanced dv/dt capabilities offer improved ruggedness.
- Higher Gate voltage threshold offers improved noise immunity.



## Absolute Maximum Ratings

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	38	A
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	24	
I <sub>DM</sub>	Pulsed Drain Current ①	150	
P <sub>D</sub> @ T <sub>C</sub> = 25°C	Power Dissipation	540	W
	Linear Derating Factor	4.3	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	±30	V
dv/dt	Peak Diode Recovery dv/dt ③	19	V/ns
T <sub>J</sub>	Operating Junction and	-55 to + 150	°C
T <sub>STG</sub>	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	
	Mounting torque, 6-32 or M3 screw	1.1(10)	N•m (lb•in)

## Diode Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	—	—	38	A	MOSFET symbol showing the integral reverse p-n junction diode.
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①	—	—	150		
V <sub>SD</sub>	Diode Forward Voltage	—	—	1.5	V	T <sub>J</sub> = 25°C, I <sub>S</sub> = 38A, V <sub>GS</sub> = 0V ④
t <sub>rr</sub>	Reverse Recovery Time	—	170	250	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = 38A
		—	420	630		T <sub>J</sub> = 125°C, di/dt = 100A/μs ④
Q <sub>rr</sub>	Reverse Recovery Charge	—	830	1240	nC	T <sub>J</sub> = 25°C, I <sub>S</sub> = 38A, V <sub>GS</sub> = 0V ④
		—	2600	3900		T <sub>J</sub> = 125°C, di/dt = 100A/μs ④
I <sub>RRM</sub>	Reverse Recovery Current	—	9.1	14	A	T <sub>J</sub> = 25°C
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

## Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	600	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
ΔV <sub>(BR)DSS/ΔT<sub>J</sub></sub>	Breakdown Voltage Temp. Coefficient	—	0.41	—	V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	—	120	150	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 23A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	3.0	—	5.0	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA
I <sub>DSS</sub>	Drain-to-Source Leakage Current	—	—	50	μA	V <sub>DS</sub> = 600V, V <sub>GS</sub> = 0V
		—	—	2.0	mA	V <sub>DS</sub> = 480V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125°C
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	—	—	100	nA	V <sub>GS</sub> = 30V
	Gate-to-Source Reverse Leakage	—	—	-100	nA	V <sub>GS</sub> = -30V
R <sub>G</sub>	Internal Gate Resistance	—	1.2	—	Ω	f = 1MHz, open drain

## Dynamic @ T<sub>J</sub> = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
g <sub>fs</sub>	Forward Transconductance	20	—	—	S	V <sub>DS</sub> = 50V, I <sub>D</sub> = 23A
Q <sub>g</sub>	Total Gate Charge	—	—	320	nC	I <sub>D</sub> = 38A V <sub>DS</sub> = 480V V <sub>GS</sub> = 10V, See Fig. 7 & 15 ④
Q <sub>gs</sub>	Gate-to-Source Charge	—	—	85		
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge	—	—	160		
t <sub>d(on)</sub>	Turn-On Delay Time	—	44	—	ns	V <sub>DD</sub> = 300V I <sub>D</sub> = 38A R <sub>G</sub> = 4.3Ω V <sub>GS</sub> = 10V, See Fig. 11a & 11b ④
t <sub>r</sub>	Rise Time	—	130	—		
t <sub>d(off)</sub>	Turn-Off Delay Time	—	92	—		
t <sub>f</sub>	Fall Time	—	69	—		
C <sub>iss</sub>	Input Capacitance	—	7990	—	pF	V <sub>GS</sub> = 0V V <sub>DS</sub> = 25V f = 1.0MHz, See Fig. 5 V <sub>GS</sub> = 0V, V <sub>DS</sub> = 0V to 480V ⑤
C <sub>oss</sub>	Output Capacitance	—	740	—		
C <sub>riss</sub>	Reverse Transfer Capacitance	—	72	—		
C <sub>oss eff.</sub>	Effective Output Capacitance	—	350	—		
C <sub>oss eff. (ER)</sub>	Effective Output Capacitance (Energy Related)	—	260	—		

## Avalanche Characteristics

Symbol	Parameter	Typ.	Max.	Units
E <sub>AS</sub>	Single Pulse Avalanche Energy②	—	680	mJ
I <sub>AR</sub>	Avalanche Current ①	—	38	A
E <sub>AR</sub>	Repetitive Avalanche Energy ①	—	54	mJ

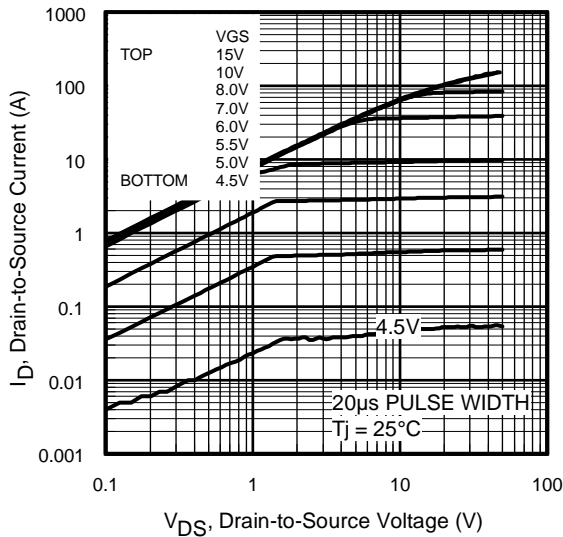
## Thermal Resistance

Symbol	Parameter	Typ.	Max.	Units
R <sub>θJC</sub>	Junction-to-Case⑥	—	0.22	°C/W
R <sub>θCS</sub>	Case-to-Sink, Flat, Greased Surface	0.24	—	
R <sub>θJA</sub>	Junction-to-Ambient⑥	—	40	

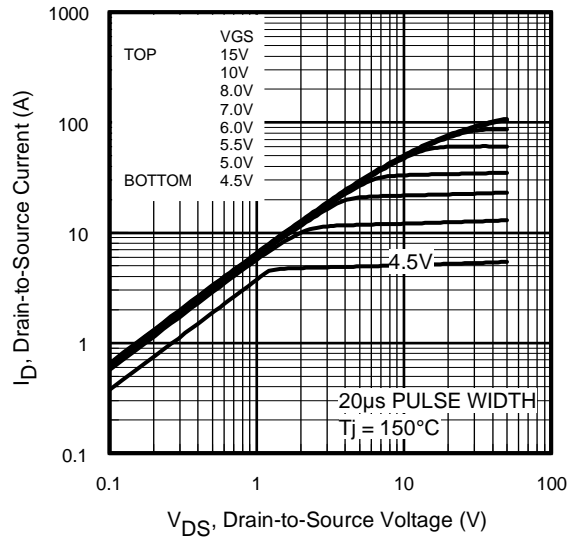
### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See Fig.12)
- ② Starting T<sub>J</sub> = 25°C, L = 0.91mH, R<sub>G</sub> = 25Ω, I<sub>AS</sub> = 38A, (See Figure 14a)
- ③ I<sub>SD</sub> ≤ 38A, di/dt ≤ 947A/μs, V<sub>DD</sub> ≤ V<sub>(BR)DSS</sub>, T<sub>J</sub> ≤ 150°C.

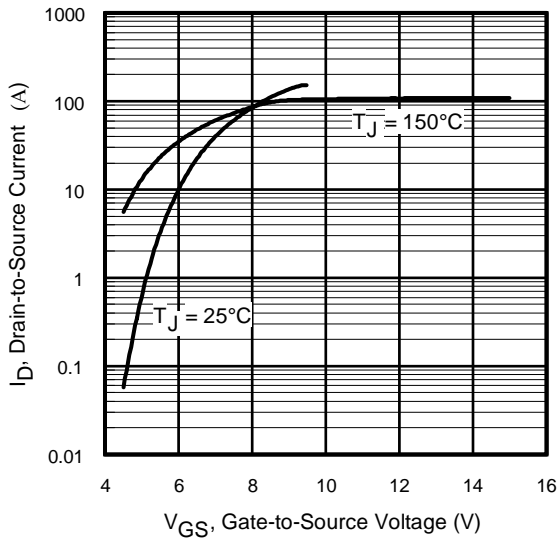
- ④ Pulse width ≤ 300μs; duty cycle ≤ 2%.
- ⑤ C<sub>oss eff.</sub> is a fixed capacitance that gives the same charging time as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 to 80% V<sub>DSS</sub>.  
C<sub>oss eff.(ER)</sub> is a fixed capacitance that stores the same energy as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 to 80% V<sub>DSS</sub>.
- ⑥ R<sub>θ</sub> is measured at T<sub>J</sub> approximately 90°C



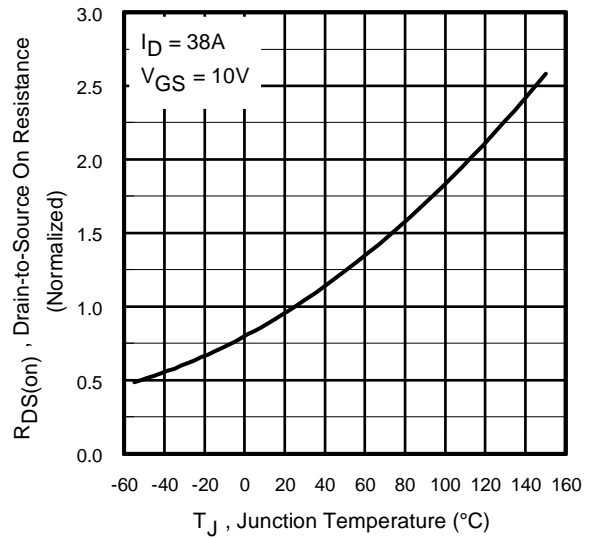
**Fig 1.** Typical Output Characteristics



**Fig 2.** Typical Output Characteristics



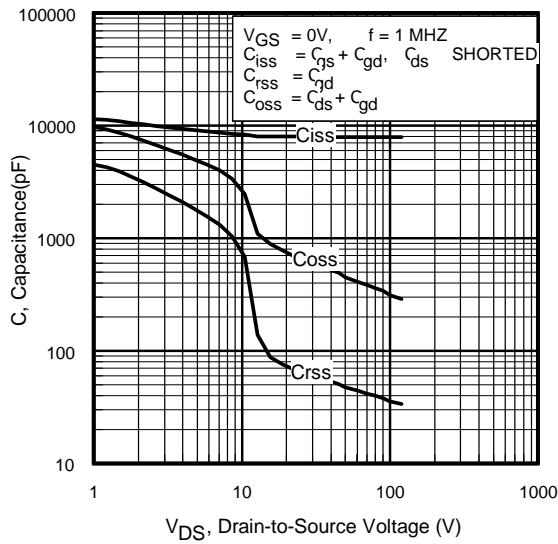
**Fig 3.** Typical Transfer Characteristics



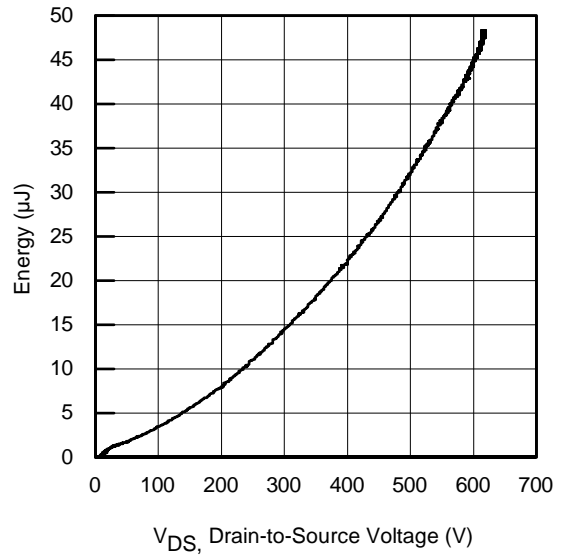
**Fig 4.** Normalized On-Resistance vs. Temperature

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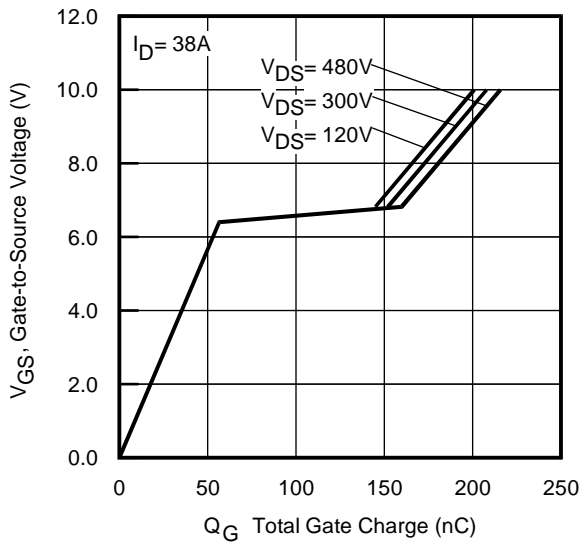
International  
**IR** Rectifier



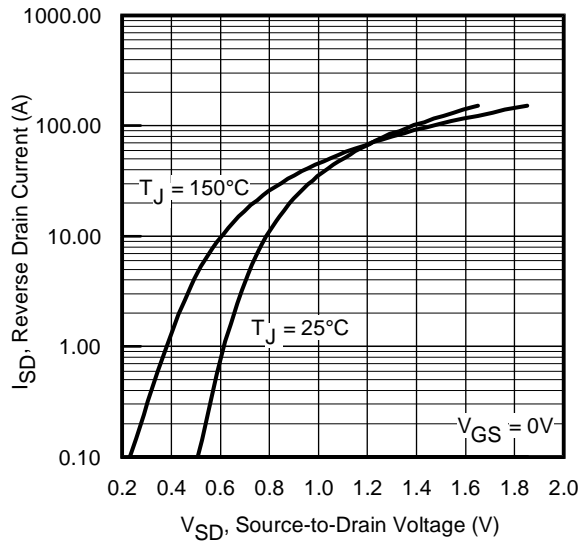
**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage



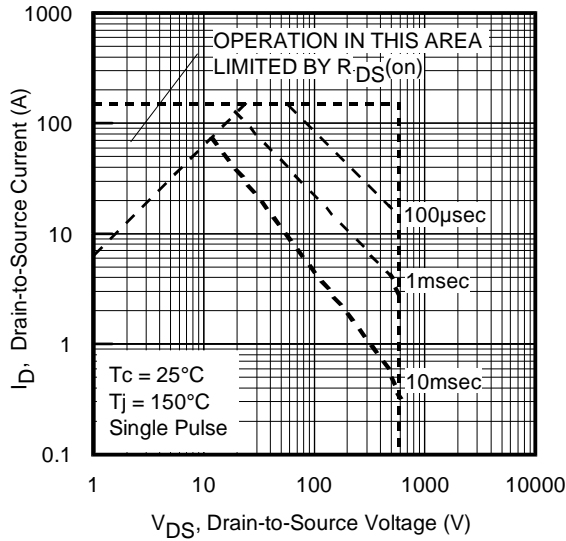
**Fig 6.** Typ. Output Capacitance Stored Energy vs.  $V_{DS}$



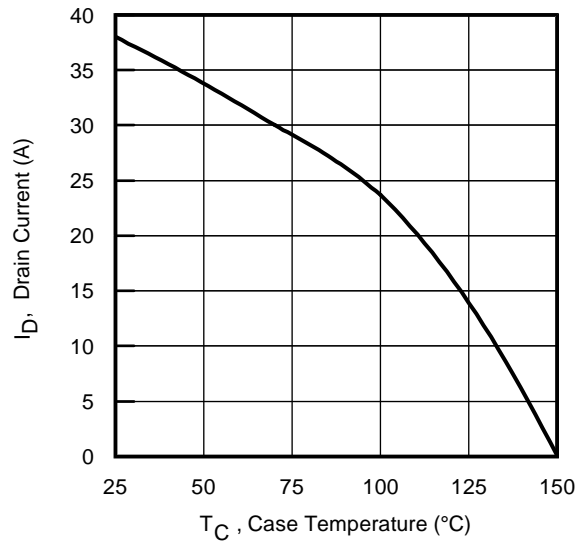
**Fig 7.** Typical Gate Charge vs. Gate-to-Source Voltage



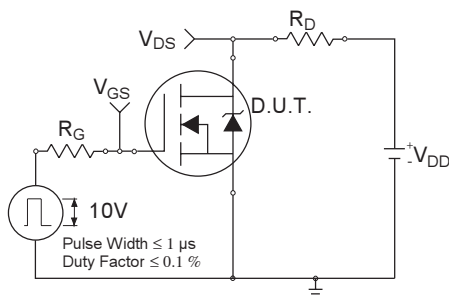
**Fig 8.** Typical Source-Drain Diode Forward Voltage



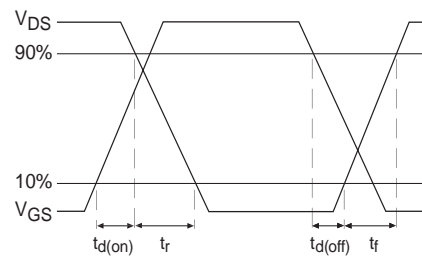
**Fig 9.** Maximum Safe Operating Area



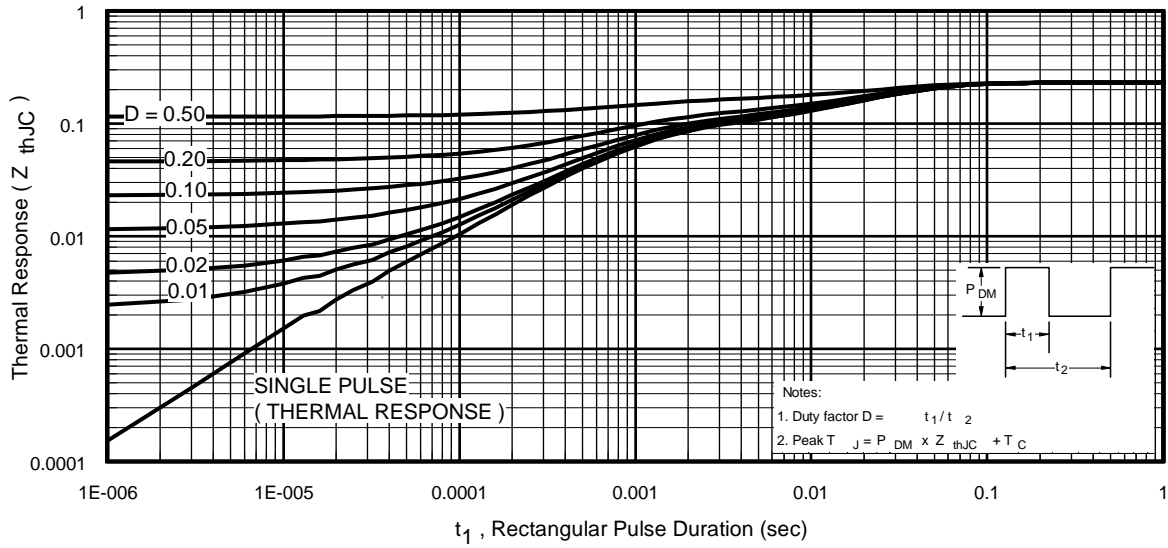
**Fig 10.** Maximum Drain Current vs. Case Temperature



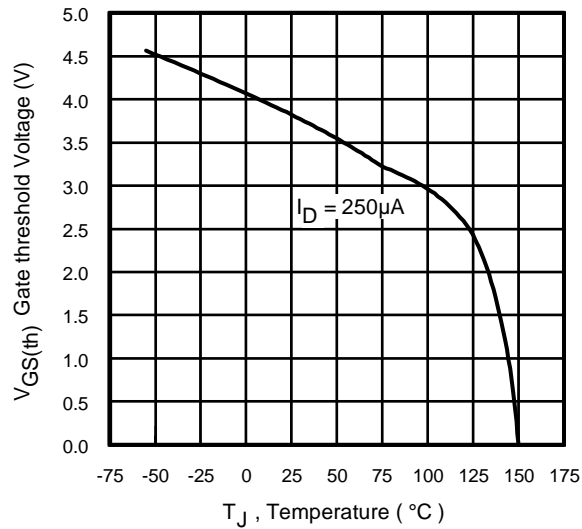
**Fig 11a.** Switching Time Test Circuit



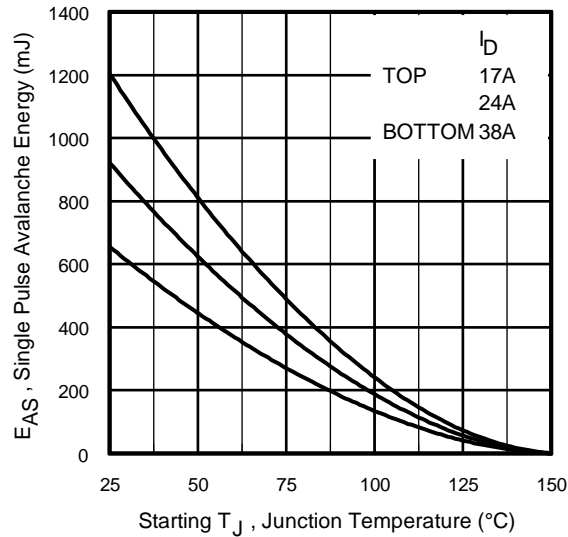
**Fig 11b.** Switching Time Waveforms



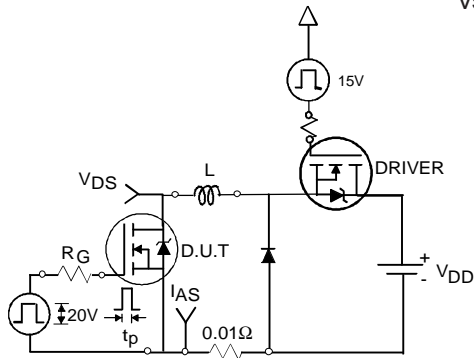
**Fig 12.** Maximum Effective Transient Thermal Impedance, Junction-to-Case



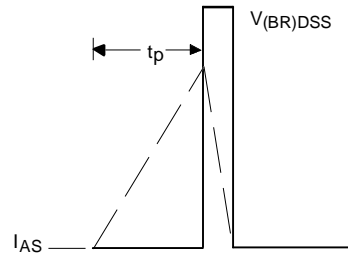
**Fig 13.** Threshold Voltage vs. Temperature



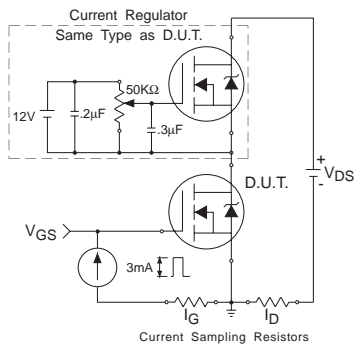
**Fig 14a.** Maximum Avalanche Energy vs. Drain Current



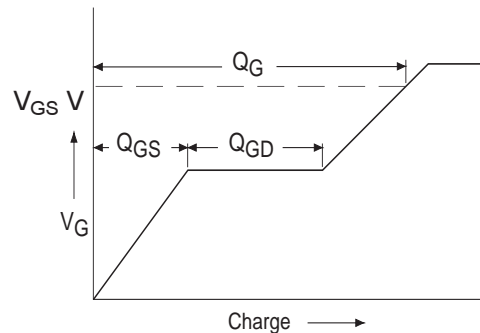
**Fig 14b.** Unclamped Inductive Test Circuit



**Fig 14c.** Unclamped Inductive Waveforms

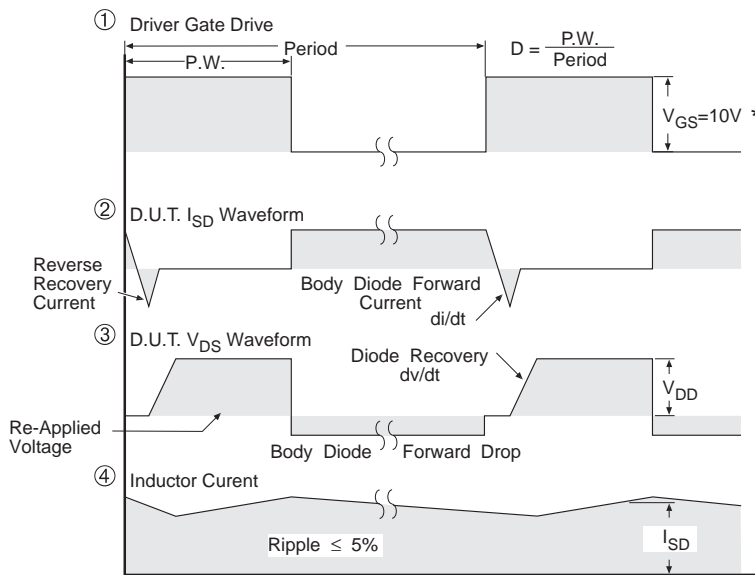
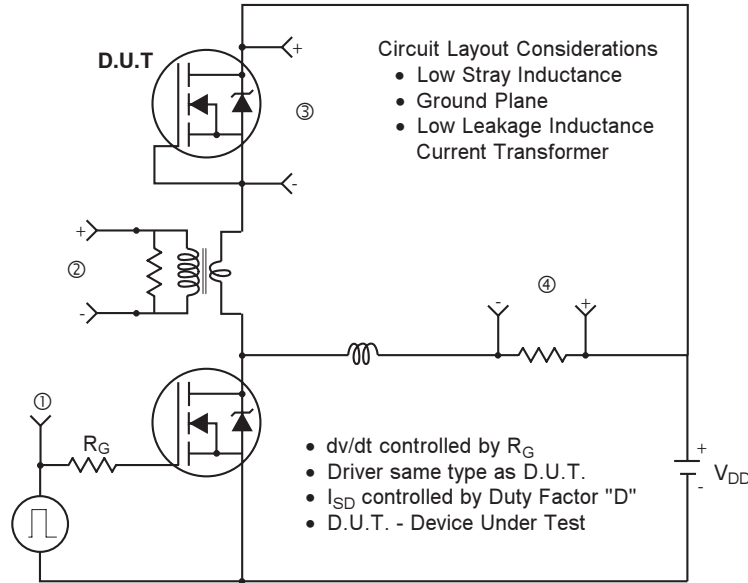


**Fig 15a.** Gate Charge Test Circuit



**Fig 15b.** Basic Gate Charge Waveform

## Peak Diode Recovery dv/dt Test Circuit

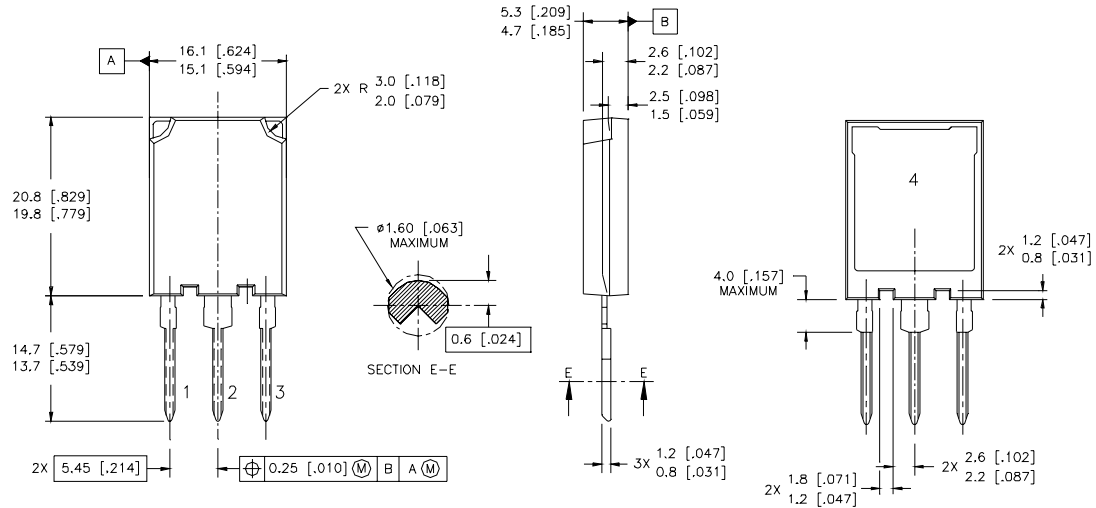


\*  $V_{GS} = 5V$  for Logic Level Devices

**Fig 16.** For N-Channel HEXFET® Power MOSFETs



## Case Outline and Dimensions — Super-247



**NOTES:**

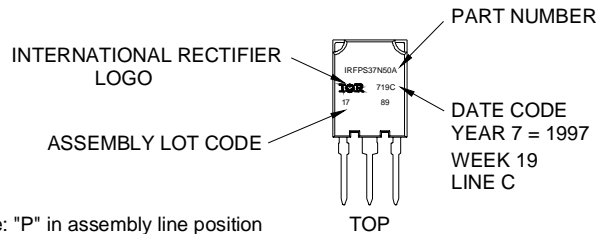
1. DIMENSIONS & TOLERANCING PER ASME Y14.5M-1994
2. CONTROLLING DIMENSION: MILLIMETER
3. DIMENSIONS ARE SHOWN IN MILLIMETRES [INCHES]

**LEAD ASSIGNMENTS**

MOSFET	IGBT
1 - GATE	1 - GATE
2 - DRAIN	2 - COLLECTOR
3 - SOURCE	3 - EMITTER
4 - DRAIN	4 - COLLECTOR

## Super-247 (TO-274AA) Part Marking Information

EXAMPLE: THIS IS AN IRFPS37N50A WITH  
 ASSEMBLY LOT CODE 1789  
 ASSEMBLED ON WW 19, 1997  
 IN THE ASSEMBLY LINE "C"



Note: "P" in assembly line position indicates "Lead-Free"

**Super TO-247AC package is not recommended for Surface Mount Application.**

Data and specifications subject to change without notice.  
 This product has been designed and qualified for the Industrial market.  
 Qualification Standards can be found on IR's Web site.